

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re: Adam William Saxler

Serial No.: To Be Assigned

Filed: Concurrently Herewith

For: HETEROGENEOUS BANDGAP STRUCTURES FOR SEMICONDUCTOR
DEVICES AND MANUFACTURING METHODS THEREFOR

Date: July 14, 2003

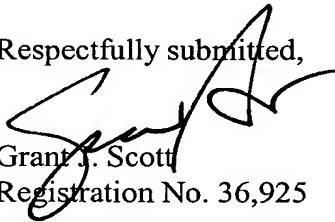
Mail Stop Patent Application
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

Attached is a list of documents on form PTO-1449 together with a copy of each identified document. It is requested that these documents be considered by the Examiner and officially made of record in accordance with the provisions of 37 C.F.R. § 1.97 and Section 609 of the MPEP.

No fee is believed due. However, the Commissioner is hereby authorized to charge any deficiency or credit any overpayment to our Deposit Account No. 50-0220.

Respectfully submitted,

Grant J. Scott
Registration No. 36,925

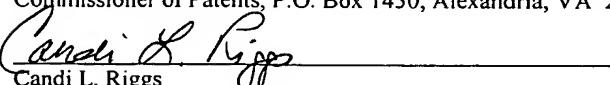


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PATENT TRADEMARK OFFICE

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Candi L. Riggs

FORM PTO-1449 U.S. Department of Commerce Patent and Trademark Office		Attorney Docket Number 5308-247	Serial No. To Be Assigned
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)		Applicants: Adam William Saxler	
		Filing Date: Concurrently Herewith	Group

U. S. PATENTS & PATENT APPLICATION PUBLICATIONS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
	1	6,507,105	1/14/03	Yamagata et al.	257	720	
	2	6,500,694	12/31/02	Enquist	438	109	
	3	6,486,499	11/26/02	Krames et al.	257	81	
	4	6,444,896	9/3/02	Harman et al.	136	239	
	5	6,201,262	3/13/01	Edmond et al.	257	77	
	6	6,323,053	11/27/01	Nishikawa et al.	438	46	
	7	6,187,606	2/13/01	Edmond et al.	438	46	
	8	6,120,600	9/19/00	Edmond et al.	117	89	
	9	6,087,674	7/11/00	Ovshinsky et al.	257	2	
	10	5,932,899	8/3/99	Schubert	257	191	
	11	5,912,477	6/15/99	Negley	257	95	
	12	5,831,277	11/3/98	Razeghi	257	15	
	13	5,739,554	4/14/98	Edmond et al.	257	103	
	14	5,631,190	5/20/97	Negley	438	33	
	15	5,682,041	10/28/97	Kawakubo et al.	257	38	
	16	5,604,135	2/18/97	Edmond et al.	437	22	
	17	5,523,589	6/4/96	Edmond et al.	257	77	
	18	5,416,342	5/16/95	Edmond et al.	257	76	
	19	5,393,993	2/28/95	Edmond et al.	257	77	
	20	5,338,944	8/16/94	Edmond et al.	257	76	
	21	5,201,051	4/6/93	Koide	395	725	
	22	5,027,168	6/25/91	Edmond	357	17	
	23	4,966,862	10/30/90	Edmond	437	100	
	24	4,918,497	4/17/90	Edmond	357	17	

EXAMINER

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Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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		Filing Date: Concurrently Herewith	Group

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation Yes No
	25	WO02/48434	6/20/02	PCT			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

28	Saxler et al., "Aluminum gallium nitride short-period superlattices doped with magnesium," Applied Physics Letters, Volume 74, Number 14, 5 April 1999, pp. 2023-2025
27	Kozodoy et al., "Polarization-enhanced Mg doping of AlGaN/GaN superlattices," Applied Physics Letters, Volume 75, Number 16, 18 October 1999, pp. 2444-2446
28	Saxler, "A review of the electrical properties of Al _x Ga _{1-x} N materials for UV photodetector applications," Photodetectors: Materials and Devices V, Proceedings of SPIE, Vol. 3948 (2000), pp. 330-341
29	Saxler et al., "Electrical characterization of Al _x Ga _{1-x} N for UV photodetector applications," SPIE Vol. 3629, January 1999, pp. 211-222

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